

BT Imaging to Attend SNEC 8th (2014) International Photovoltaic Power Generation Conference & Exhibition

- Market introduction of two new software packages for the manufacturers of silicon wafers and silicon solar cells and also for R&D researchers in photovoltaics

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SHANGHAI, China, May 14, 2014 /PRNewswire/ -- BT Imaging will be attending the SNEC (2014) International Photovoltaic Power Generation Conference & Exhibition on May 20th through May 22nd, 2014. BT Imaging will be at Booth 225 in the E3 Hall. BT Imaging will showcase two of its latest software packages which are optional upgrades for its existing LIS-R2 photoluminescence imaging laboratory measurement tool and also for the QS-W2 wafer inspection system. The LIS-R2 software upgrade is focused on giving researchers hitherto unavailable information about their solar wafers and cells. The QS-W2 software upgrade is focused on helping wafer and cell manufactures reduce costs and improve the average solar efficiency of their products.



*[BT Imaging Logo – also attached to the document]*

"We view the SNEC show in China as the major annual event for the PV Industry and we are very pleased that the timing of the SNEC show coincides with a couple of major announcements that we have for the PV Industry," said Ian Maxwell, CEO of BT Imaging. "Since BT Imaging last attended SNEC we have been working very hard on improving our existing products. The new software upgrade products that we are demonstrating at SNEC 2014 are the culmination of many years of R&D effort and we think that our customers are going to be quite excited about these products."

Beyond these announcements, BT Imaging will also feature two of its current stable of products – the LIS-R2 and the QS-W2. The LIS-R2 is the industry gold-standard laboratory measurement tool for bricks, wafers, cells and modules. BT Imaging calls the LIS-R2 the 'Swiss army knife' for photovoltaic laboratories because it incorporates so many measurement types into one simple-to-use product. It is suitable for R&D, quality control, quality assurance, process debug, process improvement and commissioning. The QS-W2 is the world's leading wafer inspection system that also incorporates photoluminescence imaging. Unlike other wafer inspection systems the QS-W2 is production-proven for the pre-sorting and rejection of wafers based upon their predicted cell efficiency.

To learn more about BT Imaging's new products and services for the photovoltaic industry, visit BT Imaging at this year's SNEC 8th (2014) International Photovoltaic Power Generation Conference & Exhibition, in Shanghai China at Booth 225 in the E3 Hall. You can also go to [www.btimaging.com](http://www.btimaging.com) for more information.

#### About BT Imaging

BT Imaging is the leading developer and manufacturer of photoluminescence imaging inspection tools for the photovoltaic industry. Since 2008 when it spun out of the world-renowned University of New South Wales' School of Photovoltaic and Renewable Energy Engineering, BT Imaging has forged a reputation based on innovation, an extensive patent portfolio, deep research capability, and new product development. BT Imaging's logo reads 'Innovate, Control, Yield' which reflects the company's vision to provide the manufacturers of photovoltaic wafers, cells and modules with ever-new hardware and software tools that allow unprecedented levels of cost reduction, and increases in production yield and product efficiency. Headquartered in Sydney Australia, privately-owned BT Imaging has offices in China, Taiwan and Europe, together with key distributors in Japan, South Korea and the USA.